

<b>Notice of References Cited</b>	Application/Control No. 10/747,636	Applicant(s)/Patent Under Reexamination TAGAWA ET AL.	
	Examiner Mark Eashoo, Ph.D.	Art Unit 1732	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0046275	03-2004	Tagawa et al.	264/145
*	B	US-5,429,487	07-1995	Tajima et al.	425/72.1
*	C	US-4,859,390	08-1989	Fritsch et al.	264/143
*	D	US-2004/0028899	02-2004	Peronnet-Paquin et al.	428/373
*	E	US-5,679,303	10-1997	Hayashi et al.	264/167
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004-136649 A	05-2004	Japan		
	O	JP 2002-113764	04-2002	Japan		
	P	JP 2003-1720	01-2003	Japan		
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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